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Embedded - System On Chip (SoC): The Heart of Modern Embedded Systems

Embedded - System On Chip (SoC) refers to an integrated circuit that consolidates all the essential components of a computer system into a single chip. This includes a microprocessor, memory, and other peripherals, all packed into one compact and efficient package. SoCs are designed to provide a complete computing solution, optimizing both space and power consumption, making them ideal for a wide range of embedded applications.

What are Embedded - System On Chip (SoC)?

System On Chip (SoC) integrates multiple functions of a computer or electronic system onto a single chip. Unlike traditional multi-chip solutions, SoCs combine a central

Details

Product Status	Obsolete
Architecture	MCU, FPGA
Core Processor	ARM® Cortex®-M3
Flash Size	128KB
RAM Size	16KB
Peripherals	DMA, POR, WDT
Connectivity	EBI/EMI, I ² C, SPI, UART/USART
Speed	80MHz
Primary Attributes	ProASIC®3 FPGA, 60K Gates, 1536D-Flip-Flops
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	256-LBGA
Supplier Device Package	256-FPBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a2f060m3e-fg256i

ProASIC3 FPGA Fabric

The SmartFusion cSoC family, based on the proven, low power, firm-error immune ProASIC®3 flash FPGA architecture, benefits from the advantages only flash-based devices offer:

Reduced Cost of Ownership

Advantages to the designer extend beyond low unit cost, high performance, and ease of use. Flash-based SmartFusion cSoCs are Instant On and do not need to be loaded from an external boot PROM at each power-up. On-board security mechanisms prevent access to the programming information and enable secure remote updates of the FPGA logic. Designers can perform secure remote in-system programming (ISP) to support future design iterations and critical field upgrades, with confidence that valuable IP cannot be compromised or copied. Secure ISP can be performed using the industry standard AES algorithm with MAC data authentication on the device.

Low Power

Flash-based SmartFusion cSoCs exhibit power characteristics similar to those of an ASIC, making them an ideal choice for power-sensitive applications. With SmartFusion cSoCs, there is no power-on current and no high current transition, both of which are common with SRAM-based FPGAs.

SmartFusion cSoCs also have low dynamic power consumption and support very low power time-keeping mode, offering further power savings.

Security

As the nonvolatile, flash-based SmartFusion cSoC family requires no boot PROM, there is no vulnerable external bitstream. SmartFusion cSoCs incorporate FlashLock®, which provides a unique combination of reprogrammability and design security without external overhead, advantages that only a device with nonvolatile flash programming can offer.

SmartFusion cSoCs utilize a 128-bit flash-based key lock and a separate AES key to provide security for programmed IP and configuration data. The FlashROM data in Fusion devices can also be encrypted prior to loading. Additionally, the flash memory blocks can be programmed during runtime using the AES-128 block cipher encryption standard (FIPS Publication 192).

SmartFusion cSoCs with AES-based security are designed to provide protection for remote field updates over public networks, such as the Internet, and help to ensure that valuable IP remains out of the hands of system overbuilders, system cloners, and IP thieves. As an additional security measure, the FPGA configuration data of a programmed Fusion device cannot be read back, although secure design verification is possible. During design, the user controls and defines both internal and external access to the flash memory blocks.

Security, built into the FPGA fabric, is an inherent component of the SmartFusion cSoC family. The flash cells are located beneath seven metal layers, and many device design and layout techniques have been used to make invasive attacks extremely difficult. SmartFusion cSoCs, with FlashLock and AES security, are unique in being highly resistant to both invasive and noninvasive attacks. Your valuable IP is protected with industry standard security measures, making remote ISP feasible. A SmartFusion cSoC provides the highest security available for programmable logic designs.

Single Chip

Flash-based FPGAs store their configuration information in on-chip flash cells. Once programmed, the configuration data is an inherent part of the FPGA structure, and no external configuration data needs to be loaded at system power-up (unlike SRAM-based FPGAs). Therefore, flash-based SmartFusion cSoCs do not require system configuration components such as electrically erasable programmable read-only memories (EEPROMs) or microcontrollers to load device configuration data during power-up. This reduces bill-of-materials costs and PCB area, and increases system security and reliability.

Instant On

Flash-based SmartFusion cSoCs are Instant On. Instant On SmartFusion cSoCs greatly simplify total system design and reduce total system cost by eliminating the need for complex programmable logic devices (CPLDs). SmartFusion Instant On clocking (PLLs) replace off-chip clocking resources. In addition, glitches and brownouts in system power will not corrupt the SmartFusion flash configuration. Unlike SRAM-based FPGAs, the device will not have to be reloaded when system power is restored.

This enables reduction or complete removal of expensive voltage monitor and brownout detection devices from the PCB design. Flash-based SmartFusion cSoCs simplify total system design and reduce cost and design risk, while increasing system reliability.

Immunity to Firm Errors

Firm errors occur most commonly when high-energy neutrons, generated in the atmosphere, strike a configuration cell of an SRAM FPGA. The energy of the collision can change the state of the configuration cell and thus change the logic, routing, or I/O configuration behavior in an unpredictable way.

Another source of radiation-induced firm errors is alpha particles. For alpha radiation to cause a soft or firm error, its source must be in very close proximity to the affected circuit. The alpha source must be in the package molding compound or in the die itself. While low-alpha molding compounds are being used increasingly, this helps reduce but does not entirely eliminate alpha-induced firm errors.

Firm errors are impossible to prevent in SRAM FPGAs. The consequence of this type of error can be a complete system failure. Firm errors do not occur in SmartFusion cSoCs. Once it is programmed, the flash cell configuration element of SmartFusion cSoCs cannot be altered by high energy neutrons and is therefore immune to errors from them. Recoverable (or soft) errors occur in the user data SRAMs of all FPGA devices. These can easily be mitigated by using error detection and correction (EDAC) circuitry built into the FPGA fabric.

Specifying I/O States During Programming

You can modify the I/O states during programming in FlashPro. In FlashPro, this feature is supported for PDB files generated from Designer v8.5 or greater. See the [FlashPro User's Guide](#) for more information.

Note: PDB files generated from Designer v8.1 to Designer v8.4 (including all service packs) have limited display of Pin Numbers only.

The I/Os are controlled by the JTAG Boundary Scan register during programming, except for the analog pins (AC, AT and AV). The Boundary Scan register of the AG pin can be used to enable/disable the gate driver in software v9.0.

1. Load a PDB from the FlashPro GUI. You must have a PDB loaded to modify the I/O states during programming.
2. From the FlashPro GUI, click PDB Configuration. A FlashPoint – Programming File Generator window appears.
3. Click the Specify I/O States During Programming button to display the Specify I/O States During Programming dialog box.
4. Sort the pins as desired by clicking any of the column headers to sort the entries by that header. Select the I/Os you wish to modify ([Figure 1-1 on page 1-4](#)).
5. Set the I/O Output State. You can set Basic I/O settings if you want to use the default I/O settings for your pins, or use Custom I/O settings to customize the settings for each pin. Basic I/O state settings:
 - 1 – I/O is set to drive out logic High
 - 0 – I/O is set to drive out logic Low
 - Last Known State – I/O is set to the last value that was driven out prior to entering the programming mode, and then held at that value during programming
 - Z -Tri-State: I/O is tristated

Power Consumption of Various Internal Resources

Table 2-14 • Different Components Contributing to Dynamic Power Consumption in SmartFusion cSoCs

Parameter	Definition	Power Supply		Device			Units
		Name	Domain	A2F060	A2F200	A2F500	
PAC1	Clock contribution of a Global Rib	VCC	1.5 V	3.39	3.40	5.05	μW/MHz
PAC2	Clock contribution of a Global Spine	VCC	1.5 V	1.14	1.83	2.50	μW/MHz
PAC3	Clock contribution of a VersaTile row	VCC	1.5 V	1.15	1.15	1.15	μW/MHz
PAC4	Clock contribution of a VersaTile used as a sequential module	VCC	1.5 V	0.12	0.12	0.12	μW/MHz
PAC5	First contribution of a VersaTile used as a sequential module	VCC	1.5 V	0.07	0.07	0.07	μW/MHz
PAC6	Second contribution of a VersaTile used as a sequential module	VCC	1.5 V	0.29	0.29	0.29	μW/MHz
PAC7	Contribution of a VersaTile used as a combinatorial module	VCC	1.5 V	0.29	0.29	0.29	μW/MHz
PAC8	Average contribution of a routing net	VCC	1.5 V	1.04	0.79	0.79	μW/MHz
PAC9	Contribution of an I/O input pin (standard dependent)	VCCxxxxIOBx/VCC	See Table 2-10 and Table 2-11 on page 2-11				
PAC10	Contribution of an I/O output pin (standard dependent)	VCCxxxxIOBx/VCC	See Table 2-12 and Table 2-13 on page 2-11				
PAC11	Average contribution of a RAM block during a read operation	VCC	1.5 V	25.00			μW/MHz
PAC12	Average contribution of a RAM block during a write operation	VCC	1.5 V	30.00			μW/MHz
PAC13	Dynamic Contribution for PLL	VCC	1.5 V	2.60			μW/MHz
PAC15	Contribution of NVM block during a read operation (F < 33MHz)	VCC	1.5 V	358.00			μW/MHz
PAC16	1st contribution of NVM block during a read operation (F > 33MHz)	VCC	1.5 V	12.88			mW
PAC17	2nd contribution of NVM block during a read operation (F > 33MHz)	VCC	1.5 V	4.80			μW/MHz
PAC18	Main Crystal Oscillator contribution	VCCMAINXTAL	3.3 V	1.98			mW
PAC19a	RC Oscillator contribution	VCCRCOSC	3.3 V	3.30			mW
PAC19b	RC Oscillator contribution	VCC	1.5 V	3.00			mW
PAC20a	Analog Block Dynamic Power Contribution of the ADC	VCC33ADCx	3.3 V	8.25			mW
PAC20b	Analog Block Dynamic Power Contribution of the ADC	VCC15ADCx	1.5 V	3.00			mW
PAC21	Low Power Crystal Oscillator contribution	VCCLPXTAL	3.3 V	33.00			μW
PAC22	MSS Dynamic Power Contribution – Running Drysthone at 100MHz ¹	VCC	1.5 V	67.50			mW
PAC23	Temperature Monitor Power Contribution	See Table 2-94 on page 2-79	–	1.23			mW

Timing Characteristics

Table 2-50 • 1.8 V LVCMOS High Slew

Worst Commercial-Case Conditions: $T_J = 85^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$,

Worst-Case $V_{CC} \times \text{IOBx} = 1.7\text{ V}$

Applicable to FPGA I/O Banks, I/O Assigned to EMC I/O Pins

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	0.60	11.06	0.04	1.14	0.39	8.61	11.06	2.61	1.59	10.67	13.12	ns
	–1	0.50	9.22	0.03	0.95	0.32	7.17	9.22	2.18	1.33	8.89	10.93	ns
4 mA	Std.	0.60	6.46	0.04	1.14	0.39	5.53	6.46	3.04	2.66	7.59	8.51	ns
	–1	0.50	5.38	0.03	0.95	0.32	4.61	5.38	2.54	2.22	6.33	7.10	ns
6 mA	Std.	0.60	4.16	0.04	1.14	0.39	3.99	4.16	3.34	3.18	6.05	6.22	ns
	–1	0.50	3.47	0.03	0.95	0.32	3.32	3.47	2.78	2.65	5.04	5.18	ns
8 mA	Std.	0.60	3.69	0.04	1.14	0.39	3.76	3.67	3.40	3.31	5.81	5.73	ns
	–1	0.50	3.07	0.03	0.95	0.32	3.13	3.06	2.84	2.76	4.85	4.78	ns
12 mA	Std.	0.60	3.38	0.04	1.14	0.39	3.44	2.86	3.50	3.82	5.50	4.91	ns
	–1	0.50	2.81	0.03	0.95	0.32	2.87	2.38	2.92	3.18	4.58	4.10	ns
16 mA	Std.	0.60	3.38	0.04	1.14	0.39	3.44	2.86	3.50	3.82	5.50	4.91	ns
	–1	0.50	2.81	0.03	0.95	0.32	2.87	2.38	2.92	3.18	4.58	4.10	ns

Notes:

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-9](#) for derating values.

Table 2-51 • 1.8 V LVCMOS Low Slew

Worst Commercial-Case Conditions: $T_J = 85^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$,

Worst-Case $V_{CC} \times \text{IOBx} = 1.7\text{ V}$

Applicable to FPGA I/O Banks, I/O Assigned to EMC I/O Pins

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	0.60	14.24	0.04	1.14	0.39	13.47	14.24	2.62	1.54	15.53	16.30	ns
	–1	0.50	11.87	0.03	0.95	0.32	11.23	11.87	2.18	1.28	12.94	13.59	ns
4 mA	Std.	0.60	9.74	0.04	1.14	0.39	9.92	9.62	3.05	2.57	11.98	11.68	ns
	–1	0.50	8.11	0.03	0.95	0.32	8.26	8.02	2.54	2.14	9.98	9.74	ns
6 mA	Std.	0.60	7.67	0.04	1.14	0.39	7.81	7.24	3.34	3.08	9.87	9.30	ns
	–1	0.50	6.39	0.03	0.95	0.32	6.51	6.03	2.79	2.56	8.23	7.75	ns
8 mA	Std.	0.60	7.15	0.04	1.14	0.39	7.29	6.75	3.41	3.21	9.34	8.80	ns
	–1	0.50	5.96	0.03	0.95	0.32	6.07	5.62	2.84	2.68	7.79	7.34	ns
12 mA	Std.	0.60	6.76	0.04	1.14	0.39	6.89	6.75	3.50	3.70	8.95	8.81	ns
	–1	0.50	5.64	0.03	0.95	0.32	5.74	5.62	2.92	3.08	7.46	7.34	ns
16 mA	Std.	0.60	6.76	0.04	1.14	0.39	6.89	6.75	3.50	3.70	8.95	8.81	ns
	–1	0.50	5.64	0.03	0.95	0.32	5.74	5.62	2.92	3.08	7.46	7.34	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-9](#) for derating values.

Table 2-66 • Minimum and Maximum DC Input and Output Levels

DC Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Units
VCCFPGAIOBx	Supply Voltage	3.0		3.3		3.6		V
VOL	Output Low Voltage	0.96	1.27	1.06	1.43	1.30	1.57	V
VOH	Output High Voltage	1.8	2.11	1.92	2.28	2.13	2.41	V
VIL, VIH	Input Low, Input High Voltages	0	3.6	0	3.6	0	3.6	V
VODIFF	Differential Output Voltage	0.625	0.97	0.625	0.97	0.625	0.97	V
VOCM	Output Common-Mode Voltage	1.762	1.98	1.762	1.98	1.762	1.98	V
VICM	Input Common-Mode Voltage	1.01	2.57	1.01	2.57	1.01	2.57	V
VIDIFF	Input Differential Voltage	300		300		300		mV

Table 2-67 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	V _{REF} (typ.) (V)
1.64	1.94	Cross point	–

* Measuring point = V_{trip} . See [Table 2-22 on page 2-24](#) for a complete table of trip points.

Timing Characteristics

Table 2-68 • LVPECL

Worst Commercial-Case Conditions: $T_J = 85^{\circ}\text{C}$, Worst-Case VCC = 1.425 V,

Worst-Case VCCFPGAIOBx = 3.0 V

Applicable to FPGA I/O Banks, I/O Assigned to EMC I/O Pins

Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	Units
Std.	0.60	1.76	0.04	1.76	ns
–1	0.50	1.46	0.03	1.46	ns

Notes:

- For the derating values at specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-9](#) for derating values.
- The above mentioned timing parameters correspond to 24mA drive strength.

Global Resource Characteristics

A2F200 Clock Tree Topology

Clock delays are device-specific. [Figure 2-27](#) is an example of a global tree used for clock routing. The global tree presented in [Figure 2-27](#) is driven by a CCC located on the west side of the A2F200 device. It is used to drive all D-flip-flops in the device.

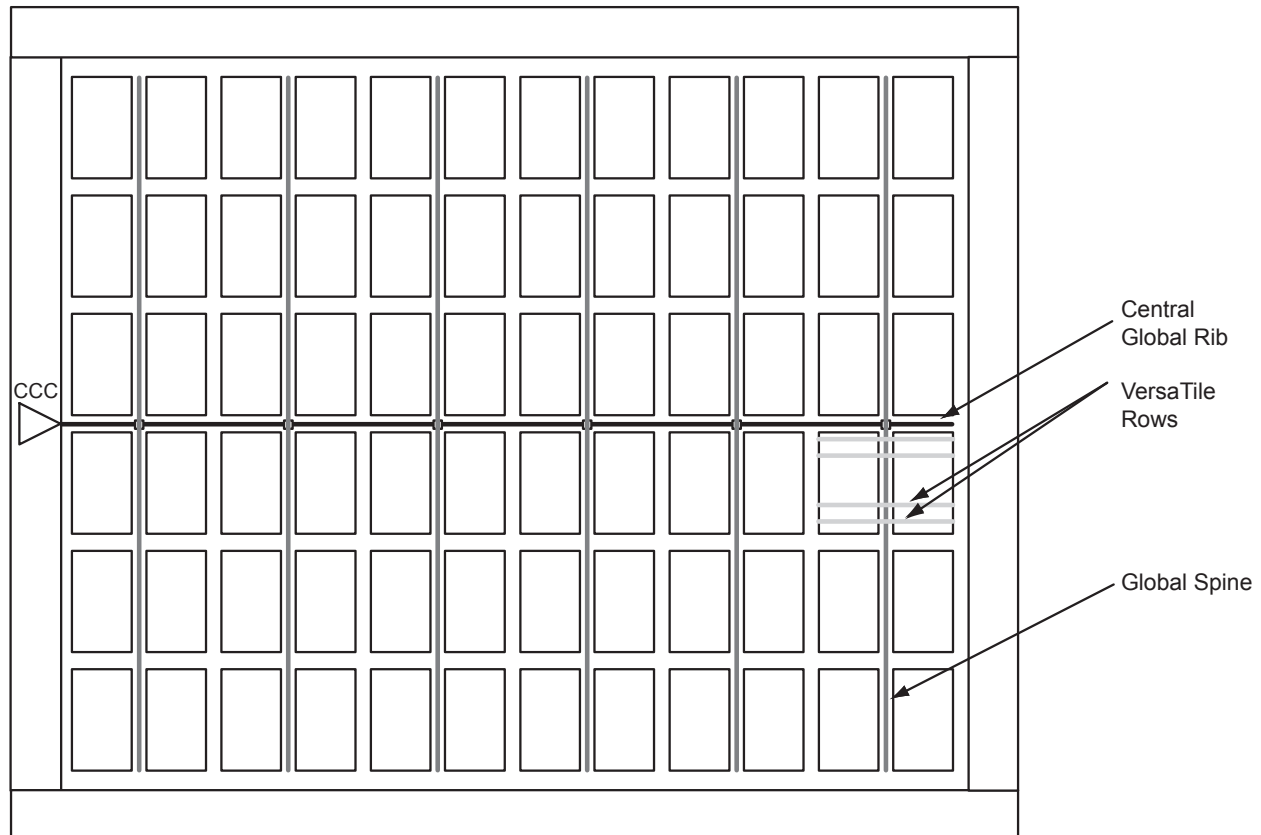


Figure 2-27 • Example of Global Tree Use in an A2F200 Device for Clock Routing

Global Tree Timing Characteristics

Global clock delays include the central rib delay, the spine delay, and the row delay. Delays do not include I/O input buffer clock delays, as these are I/O standard-dependent, and the clock may be driven and conditioned internally by the CCC module. For more details on clock conditioning capabilities, refer to the ["Clock Conditioning Circuits" section on page 2-63](#). [Table 2-80](#) through [Table 2-82 on page 2-61](#) present minimum and maximum global clock delays for the SmartFusion cSoCs. Minimum and maximum delays are measured with minimum and maximum loading.

FPGA Fabric SRAM and FIFO Characteristics

FPGA Fabric SRAM

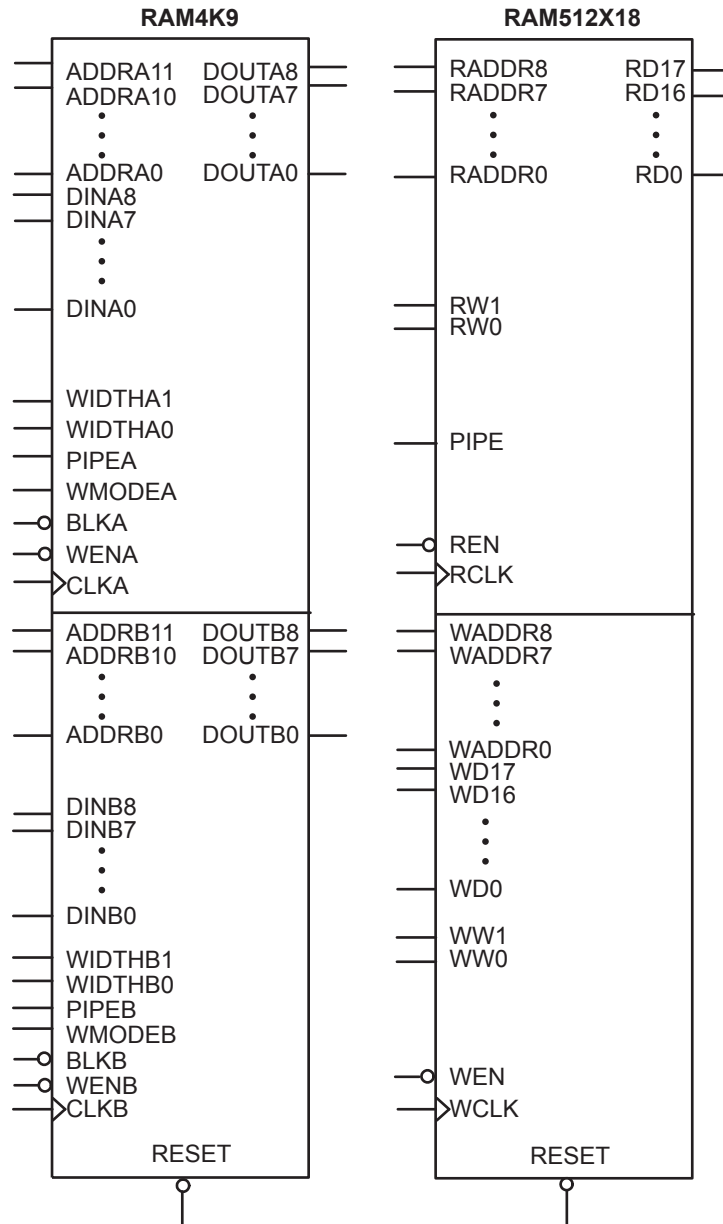


Figure 2-29 • RAM Models

Table 2-92 • JTAG 1532**Worst Commercial-Case Conditions: $T_J = 85^{\circ}\text{C}$, Worst-Case VCC = 1.425 V**

Parameter	Description	–1	Std.	Units
t_{RSTB2Q}	Reset to Q (data out)	26.67	30.67	ns
F_{TCKMAX}	TCK Maximum Frequency	19.00	21.85	MHz
t_{TRSTREM}	ResetB Removal Time	0.00	0.00	ns
t_{TRSTREC}	ResetB Recovery Time	0.27	0.31	ns
t_{TRSTMPW}	ResetB Minimum Pulse	TBD	TBD	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-9](#) for derating values.

Comparator

Unless otherwise specified, performance is specified at 25°C with nominal power supply voltages.

Table 2-97 • Comparator Performance Specifications

Specification	Test Conditions		Min.	Typ.	Max.	Units
Input voltage range	Minimum			0		V
	Maximum			2.56		V
Input offset voltage	HYS[1:0] = 00 (no hysteresis)			±1	±3	mV
Input bias current	Comparator 1, 3, 5, 7, 9 (measured at 2.56 V)			40	100	nA
	Comparator 0, 2, 4, 6, 8 (measured at 2.56 V)			150	300	nA
Input resistance			10			M :
Power supply rejection ratio	DC (0 – 10 KHz)		50	60		dB
Propagation delay	100 mV overdrive					
	HYS[1:0] = 00					
	(no hysteresis)			15	18	ns
	100 mV overdrive					
	HYS[1:0] = 10					
	(with hysteresis)			25	30	ns
Hysteresis (± refers to rising and falling threshold shifts, respectively)	HYS[1:0] = 00	Typical (25°C)	0	0	±5	mV
		Across all corners (–40°C to +100°C)	0		±5	mV
	HYS[1:0] = 01	Typical (25°C)	±3	± 16	±30	mV
		Across all corners (–40°C to +100°C)	0		±36	mV
	HYS[1:0] = 10	Typical (25°C)	±19	± 31	±48	mV
		Across all corners (–40°C to +100°C)	±12		±54	mV
	HYS[1:0] = 11	Typical (25°C)	±80	± 105	±190	mV
		Across all corners (–40°C to +100°C)	±80		±194	mV
Comparator current requirements (per comparator)	VCC33A = 3.3 V (operational mode); COMP_EN = 1					
	VCC33A			150	165	µA
	VCC33AP			140	165	µA
	VCC15A			1	3	µA

Inter-Integrated Circuit (I²C) Characteristics

This section describes the DC and switching of the I²C interface. Unless otherwise noted, all output characteristics given are for a 100 pF load on the pins. For timing parameter definitions, refer to [Figure 2-48 on page 2-92](#).

Table 2-101 • I²C Characteristics

Commercial Case Conditions: T_J = 85°C, V_{DD} = 1.425 V, –1 Speed Grade

Parameter	Definition	Condition	Value	Unit
V _{IL}	Minimum input low voltage	–	See Table 2-36 on page 2-30	–
	Maximum input low voltage	–	See Table 2-36	–
V _{IH}	Minimum input high voltage	–	See Table 2-36	–
	Maximum input high voltage	–	See Table 2-36	–
V _{OL}	Maximum output voltage low	I _{OL} = 8 mA	See Table 2-36	–
I _{IL}	Input current high	–	See Table 2-36	–
I _{IH}	Input current low	–	See Table 2-36	–
V _{hyst}	Hysteresis of Schmitt trigger inputs	–	See Table 2-33 on page 2-29	V
T _{FALL}	Fall time ²	VIHmin to VILMax, C _{load} = 400 pF	15.0	ns
		VIHmin to VILMax, C _{load} = 100 pF	4.0	ns
T _{RISE}	Rise time ²	VILMax to VIHmin, C _{load} = 400pF	19.5	ns
		VILMax to VIHmin, C _{load} = 100pF	5.2	ns
C _{in}	Pin capacitance	V _{IN} = 0, f = 1.0 MHz	8.0	pF
R _{pull-up}	Output buffer maximum pull-down Resistance ¹	–	50	:
R _{pull-down}	Output buffer maximum pull-up Resistance ¹	–	150	:
D _{max}	Maximum data rate	Fast mode	400	Kbps
t _{LOW}	Low period of I2C_x_SCL ³	–	1	clk cycles
t _{HIGH}	High period of I2C_x_SCL ³	–	1	clk cycles
t _{HD;STA}	START hold time ³	–	1	clk cycles
t _{SU;STA}	START setup time ³	–	1	clk cycles
t _{HD;DAT}	DATA hold time ³	–	1	clk cycles
t _{SU;DAT}	DATA setup time ³	–	1	clk cycles

Notes:

1. These maximum values are provided for information only. Minimum output buffer resistance values depend on VCCxxxIOBx, drive strength selection, temperature, and process. For board design considerations and detailed output buffer resistances, use the corresponding IBIS models located on the SoC Products Group website at http://www.microsemi.com/index.php?option=com_microsemi&Itemid=489&lang=en&view=salescontact.
2. These values are provided for a load of 100 pF and 400 pF. For board design considerations and detailed output buffer resistances, use the corresponding IBIS models located on the SoC Products Group website at http://www.microsemi.com/index.php?option=com_microsemi&Itemid=489&lang=en&view=salescontact.
3. For allowable Pclk configurations, refer to the Inter-Integrated Circuit (I²C) Peripherals section in the [SmartFusion Microcontroller Subsystem User's Guide](#).

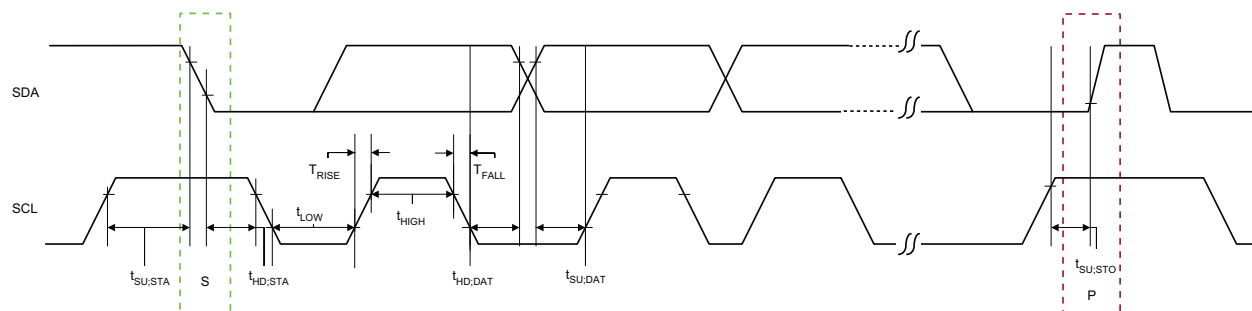
Table 2-101 • I²C Characteristics

Commercial Case Conditions: $T_J = 85^\circ\text{C}$, $V_{DD} = 1.425\text{ V}$, -1 Speed Grade (continued)

Parameter	Definition	Condition	Value	Unit
$t_{\text{SU;STO}}$	STOP setup time ³	—	1	pclk cycles
t_{FILT}	Maximum spike width filtered	—	50	ns

Notes:

1. These maximum values are provided for information only. Minimum output buffer resistance values depend on VCCxxxxIOBx, drive strength selection, temperature, and process. For board design considerations and detailed output buffer resistances, use the corresponding IBIS models located on the SoC Products Group website at http://www.microsemi.com/index.php?option=com_microsemi&Itemid=489&lang=en&view=salescontact.
2. These values are provided for a load of 100 pF and 400 pF. For board design considerations and detailed output buffer resistances, use the corresponding IBIS models located on the SoC Products Group website at http://www.microsemi.com/index.php?option=com_microsemi&Itemid=489&lang=en&view=salescontact.
3. For allowable Pclk configurations, refer to the Inter-Integrated Circuit (I²C) Peripherals section in the [SmartFusion Microcontroller Subsystem User's Guide](#).


Figure 2-48 • I²C Timing Parameter Definition

Embedded Design

Microsemi offers FREE SoftConsole Eclipse based IDE, which includes the GNU C/C++ compiler and GDB debugger. Microsemi also offers evaluation versions of software from Keil and IAR, with full versions available from respective suppliers.

Analog Design

The MSS configurator provides graphical configuration for current, voltage and temperature monitors, sample sequencing setup and post-processing configuration, as well as DAC output.

The MSS configurator creates a bridge between the FPGA fabric and embedded designers so device configuration can be easily shared between multiple developers.

The MSS configurator includes the following:

- A simple configurator for the embedded designer to control the MSS peripherals and I/Os
- A method to import and view a hardware configuration from the FPGA flow into the embedded flow containing the memory map
- Automatic generation of drivers for any peripherals or soft IP used in the system configuration
- Comprehensive analog configuration for the programmable analog components
- Creation of a standard MSS block to be used in SmartDesign for connection of FPGA fabric designs and IP

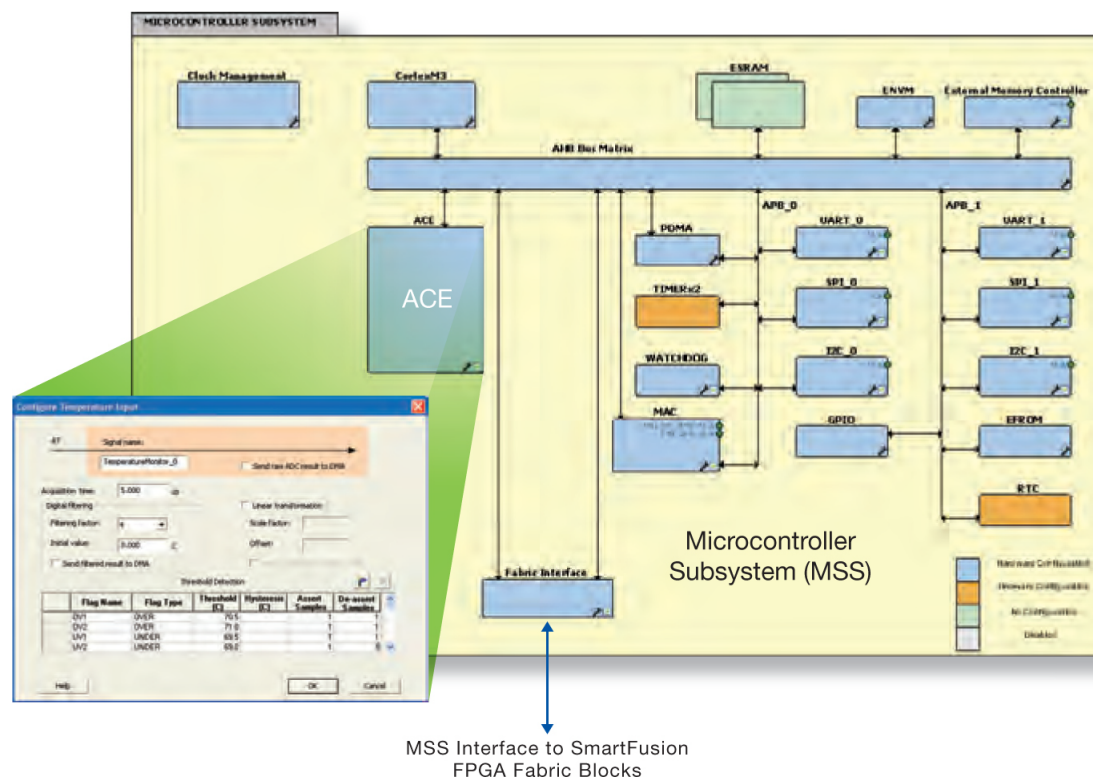


Figure 3-2 • MSS Configurator

Compile and Debug

Microsemi's SoftConsole is a free Eclipse-based IDE that enables the rapid production of C and C++ executables for Microsemi FPGA and cSoCs using Cortex-M3, Cortex-M1 and Core8051s. For SmartFusion support, SoftConsole includes the GNU C/C++ compiler and GDB debugger. Additional examples can be found on the SoftConsole page:





- [Using UART with SmartFusion: SoftConsole Standalone Flow Tutorial](#)
 - [Design Files](#)
- [Displaying POT Level with LEDs: Libero SoC and SoftConsole Flow Tutorial for SmartFusion](#)
 - [Design Files](#)

IAR Embedded Workbench® for ARM/Cortex is an integrated development environment for building and debugging embedded ARM applications using assembler, C and C++. It includes a project manager, editor, build and debugger tools with support for RTOS-aware debugging on hardware or in a simulator.

- [Designing SmartFusion cSoC with IAR Systems](#)
- [IAR Embedded Workbench IDE User Guide for ARM](#)
- [Download Evaluation or Kickstart version of IAR Embedded Workbench for ARM](#)

Keil's Microcontroller Development Kit comes in two editions: MDK-ARM and MDK Basic. Both editions feature μ Vision®, the ARM Compiler, MicroLib, and RTX, but the MDK Basic edition is limited to 256K so that small applications are more affordable.

- [Designing SmartFusion cSoC with Keil](#)
- [Using Keil \$\mu\$ Vision and Microsemi SmartFusion cSoC](#)
 - [Programming file for use with this tutorial](#)
- [Keil Microcontroller Development Kit for ARM Product Manuals](#)
- [Download Evaluation version of Keil MDK-ARM](#)

			
Software IDE	SoftConsole	Vision IDE	Embedded Workbench
Website	www.microsemi.com/soc	www.keil.com	www.iar.com
Free versions from SoC Products Group	Free with Libero SoC	32 K code limited	32 K code limited
Available from Vendor	N/A	Full version	Full version
Compiler	GNU GCC	RealView C/C++	IAR ARM Compiler
Debugger	GDB debug	Vision Debugger	C-SPY Debugger
Instruction Set Simulator	No	Vision Simulator	Yes
Debug Hardware	FlashPro4	ULINK2 or ULINK-ME	J-LINK or J-LINK Lite

Operating Systems

FreeRTOS™ is a portable, open source, royalty free, mini real-time kernel (a free-to-download and free-to-deploy RTOS that can be used in commercial applications without any requirement to expose your proprietary source code). FreeRTOS is scalable and designed specifically for small embedded systems. This FreeRTOS version ported by Microsemi is 6.0.1. For more information, visit the FreeRTOS website: www.freertos.org

- [SmartFusion Webserver Demo Using uIP and FreeRTOS](#)
- [SmartFusion cSoC: Running Webserver, TFTP on lwIP TCP/IP Stack Application Note](#)

Emcraft Systems provides porting of the open-source U-boot firmware and uClinux™ kernel to the SmartFusion cSoC, a Linux®-based cross-development framework, and other complementary components. Combined with the release of its A2F-Linux Evaluation Kit, this provides a low-cost platform for evaluation and development of Linux (uClinux) on the Cortex-M3 CPU core of the Microsemi SmartFusion cSoC.

- [Emcraft Linux on Microsemi's SmartFusion cSoC](#)

Keil offers the RTX Real-Time Kernel as a royalty-free, deterministic RTOS designed for ARM and Cortex-M devices. It allows you to create programs that simultaneously perform multiple functions and helps to create applications which are better structured and more easily maintained.

- The RTX Real-Time Kernel is included with MDK-ARM. Download the [Evaluation version of Keil MDK-ARM](#).
- RTX source code is available as part of [Keil/ARM Real-Time Library \(RL-ARM\)](#), a group of tightly-coupled libraries designed to solve the real-time and communication challenges of embedded systems based on ARM-powered microcontroller devices. The RL-ARM library now supports SmartFusion cSoCs and designers with additional key features listed in the ["Middleware" section on page 3-5](#).

Micrium supports SmartFusion cSoCs with the company's flagship µC/OS family, recognized for a variety of features and benefits, including unparalleled reliability, performance, dependability, impeccable source code and vast documentation. Micrium supports the following products for SmartFusion cSoCs and continues to work with Microsemi on additional projects.

- [SmartFusion Quickstart Guide for Micrium µC/OS-III Examples](#)
 - [Design Files](#)

µC/OS-III™, Micrium's newest RTOS, is designed to save time on your next embedded project and puts greater control of the software in your hands.

RoweBots provides an ultra tiny Linux-compatible RTOS called Unison for SmartFusion. Unison consists of a set of modular software components, which, like Linux, are either free or commercially licensed. Unison offers POSIX® and Linux compatibility with hard real-time performance, complete I/O modules and an easily understood environment for device driver programming. Seamless integration with FPGA and analog features are fast and easy.

- [Unison V4](#)-based products include a free Unison V4 Linux and POSIX-compatible kernel with serial I/O, file system, six demonstration programs, upgraded documentation and source code for Unison V4, and free (for non-commercial use) Unison V4 TCP/IP server. Commercial license upgrade is available for Unison V4 TCP/IP server with three demonstration programs, DHCP client and source code.
- [Unison V5](#)-based products include commercial Unison V5 Linux- and POSIX-compatible kernel with serial I/O, file system, extensive feature set, full documentation, source code and more than 20 demonstration programs, Unison V5 TCP/IPv4 with extended feature set, sockets interface, multiple network interfaces, PPP support, DHCP client, documentation, source code and six demonstration programs, and multiple other features.

Middleware

Microsemi has ported both uIP and lwIP for Ethernet support as well as including TFTP file service.

- [SmartFusion Webserver Demo Using uIP and FreeRTOS](#)
- [SmartFusion: Running Webserver, TFTP on lwIP TCP/IP Stack Application Note](#)

The [Keil/ARM Real-Time Library \(RL-ARM\)](#)¹, in addition to RTX source, includes the following:

- [RL-TCPnet \(TCP/IP\)](#) – The Keil RL-TCPnet library, supporting full TCP/IP and UDP protocols, is a full networking suite specifically written for small ARM and Cortex-M processor-based microcontrollers. TCPnet is now ported to and supports SmartFusion Cortex-M3. It is highly optimized, has a small code footprint, and gives excellent performance, providing a wide range of application level protocols and examples such as FTP, SNMP, SOAP and AJAX. An [HTTP server example](#) of TCPnet working in a SmartFusion design is available.

1. The CAN and USB functions within RL-ARM are not supported for SmartFusion cSoC.

Pin No.	CS288		
	A2F060 Function	A2F200 Function	A2F500 Function
C21	IO17NDB0V0	GBA2/IO20PDB1V0	GBA2/IO27PDB1V0
D1	EMC_DB[14]/IO45NDB5V0	EMC_DB[14]/GAB2/IO71NDB5V0	EMC_DB[14]/GAB2/IO88NDB5V0
D3	VCCFPGAIOB5	VCCFPGAIOB5	VCCFPGAIOB5
D19	GND	GND	GND
D21	VCCFPGAIOB1	VCCFPGAIOB1	VCCFPGAIOB1
E1	EMC_DB[13]/IO44PDB5V0	EMC_DB[13]/GAC2/IO70PDB5V0	EMC_DB[13]/GAC2/IO87PDB5V0
E3	EMC_DB[12]/IO44NDB5V0	EMC_DB[12]/IO70NDB5V0	EMC_DB[12]/IO87NDB5V0
E5	GNDQ	GNDQ	GNDQ
E6	EMC_BYTEN[0]/IO02NDB0V0	EMC_BYTEN[0]/GAC0/IO02NDB0V0	EMC_BYTEN[0]/GAC0/IO07NDB0V0
E7	EMC_BYTEN[1]/IO02PDB0V0	EMC_BYTEN[1]/GAC1/IO02PDB0V0	EMC_BYTEN[1]/GAC1/IO07PDB0V0
E8	EMC_OEN1_N/IO03PDB0V0	EMC_OEN1_N/IO03PDB0V0	EMC_OEN1_N/IO08PDB0V0
E9	EMC_AB[3]/IO05PDB0V0	EMC_AB[3]/IO05PDB0V0	EMC_AB[3]/IO09PDB0V0
E10	EMC_AB[10]/IO09NDB0V0	EMC_AB[10]/IO09NDB0V0	EMC_AB[10]/IO11NDB0V0
E11	EMC_AB[7]/IO07PDB0V0	EMC_AB[7]/IO07PDB0V0	EMC_AB[7]/IO12PDB0V0
E12	EMC_AB[13]/IO10PDB0V0	EMC_AB[13]/IO10PDB0V0	EMC_AB[13]/IO14PDB0V0
E13	EMC_AB[16]/IO12NDB0V0	EMC_AB[16]/IO12NDB0V0	EMC_AB[16]/IO17NDB0V0
E14	EMC_AB[17]/IO12PDB0V0	EMC_AB[17]/IO12PDB0V0	EMC_AB[17]/IO17PDB0V0
E15	GCC0/IO18NPB0V0	GCB0/IO27NDB1V0	GCB0/IO34NDB1V0
E16	GCA1/IO20PPB0V0	GCB1/IO27PDB1V0	GCB1/IO34PDB1V0
E17	GCC1/IO18PPB0V0	GCB2/IO24PDB1V0	GCB2/IO33PDB1V0
E19	GCB2/IO22PPB1V0	GCA0/IO28NDB1V0	GCA0/IO36NDB1V0 *
E21	IO21NDB1V0	GCA1/IO28PDB1V0	GCA1/IO36PDB1V0 *
F1	VCCFPGAIOB5	VCCFPGAIOB5	VCCFPGAIOB5
F3	GFB2/IO42NDB5V0	GFB2/IO68NDB5V0	GFB2/IO85NDB5V0
F5	GFA2/IO42PDB5V0	GFA2/IO68PDB5V0	GFA2/IO85PDB5V0
F6	EMC_DB[11]/IO43PDB5V0	EMC_DB[11]/IO69PDB5V0	EMC_DB[11]/IO86PDB5V0
F7	GND	GND	GND
F8	NC	GFC1/IO66PPB5V0	GFC1/IO83PPB5V0
F9	VCCFPGAIOB0	VCCFPGAIOB0	VCCFPGAIOB0
F10	EMC_AB[11]/IO09PDB0V0	EMC_AB[11]/IO09PDB0V0	EMC_AB[11]/IO11PDB0V0
F11	EMC_AB[6]/IO07NDB0V0	EMC_AB[6]/IO07NDB0V0	EMC_AB[6]/IO12NDB0V0

Notes:

1. Shading denotes pins that do not have completely identical functions from density to density. For example, the bank assignment can be different for an I/O, or the function might be available only on a larger density device.
2. *: Indicates that the signal assigned to the pins as a CLKBUF/CLKBUF_LVPECL/CLKBUF_LVDS goes through a glitchless mux. In order for the glitchless mux to operate correctly, the signal must be a free-running clock signal. Refer to the 'Glitchless MUX' section in the [SmartFusion Microcontroller Subsystem User's Guide](#) for more details.

Pin Number	PQ208	
	A2F200	A2F500
32	VCCRCOSC	VCCRCOSC
33	MSS_RESET_N	MSS_RESET_N
34	VCCESRAM	VCCESRAM
35	MAC_MDC/IO48RSB4V0	MAC_MDC/IO57RSB4V0
36	MAC_MDIO/IO49RSB4V0	MAC_MDIO/IO58RSB4V0
37	MAC_TXEN/IO52RSB4V0	MAC_TXEN/IO61RSB4V0
38	MAC_CRSDV/IO51RSB4V0	MAC_CRSDV/IO60RSB4V0
39	MAC_RXER/IO50RSB4V0	MAC_RXER/IO59RSB4V0
40	GND	GND
41	VCCMSSIOB4	VCCMSSIOB4
42	VCC	VCC
43	MAC_TXD[0]/IO56RSB4V0	MAC_TXD[0]/IO65RSB4V0
44	MAC_TXD[1]/IO55RSB4V0	MAC_TXD[1]/IO64RSB4V0
45	MAC_RXD[0]/IO54RSB4V0	MAC_RXD[0]/IO63RSB4V0
46	MAC_RXD[1]/IO53RSB4V0	MAC_RXD[1]/IO62RSB4V0
47	MAC_CLK	MAC_CLK
48	GNDSDD0	GNDSDD0
49	VCC33SDD0	VCC33SDD0
50	VCC15A	VCC15A
51	PCAP	PCAP
52	NCAP	NCAP
53	VCC33AP	VCC33AP
54	VCC33N	VCC33N
55	SDD0	SDD0
56	GNDA	GNDA
57	GNDAQ	GNDAQ
58	ABPS0	ABPS0
59	ABPS1	ABPS1
60	CM0	CM0
61	TM0	TM0
62	GNDTM0	GNDTM0

Notes:

1. Shading denotes pins that do not have completely identical functions from density to density. For example, the bank assignment can be different for an I/O, or the function might be available only on a larger density device.
2. *: Indicates that the signal assigned to the pins as a CLKBUF/CLKBUF_LVPECL/CLKBUF_LVDS goes through a glitchless mux. In order for the glitchless mux to operate correctly, the signal must be a free-running clock signal. Refer to the 'Glitchless MUX' section in the [SmartFusion Microcontroller Subsystem User's Guide](#) for more details.

Pin No.	FG256		
	A2F060 Function	A2F200 Function	A2F500 Function
T9	VAREF0	VAREF1	VAREF1
T10	ABPS0	ABPS6	ABPS6
T11	NC	ABPS5	ABPS5
T12	NC	SDD1	SDD1
T13	GNDVAREF	GNDVAREF	GNDVAREF
T14	GNDMAINXTAL	GNDMAINXTAL	GNDMAINXTAL
T15	VCCLPXTAL	VCCLPXTAL	VCCLPXTAL
T16	PU_N	PU_N	PU_N

Notes:

1. Shading denotes pins that do not have completely identical functions from density to density. For example, the bank assignment can be different for an I/O, or the function might be available only on a larger density device.
2. *: Indicates that the signal assigned to the pins as a CLKBUF/CLKBUF_LVPECL/CLKBUF_LVDS goes through a glitchless mux. In order for the glitchless mux to operate correctly, the signal must be a free-running clock signal. Refer to the 'Glitchless MUX' section in the [SmartFusion Microcontroller Subsystem User's Guide](#) for more details.

Pin Number	FG484	
	A2F200 Function	A2F500 Function
C15	EMC_AB[17]/IO12PDB0V0	EMC_AB[17]/IO17PDB0V0
C16	EMC_AB[24]/IO16NDB0V0	EMC_AB[24]/IO20NDB0V0
C17	EMC_AB[22]/IO15NDB0V0	EMC_AB[22]/IO19NDB0V0
C18	EMC_AB[23]/IO15PDB0V0	EMC_AB[23]/IO19PDB0V0
C19	GBA0/IO19NPB0V0	GBA0/IO23NPB0V0
C20	NC	NC
C21	GBC2/IO21PDB1V0	GBC2/IO30PDB1V0
C22	GBB2/IO20NDB1V0	GBB2/IO27NDB1V0
D1	GND	GND
D2	EMC_DB[12]/IO70NDB5V0	EMC_DB[12]/IO87NDB5V0
D3	EMC_DB[13]/GAC2/IO70PDB5V0	EMC_DB[13]/GAC2/IO87PDB5V0
D4	NC	NC
D5	NC	NC
D6	GND	GND
D7	NC	IO00NPB0V0
D8	NC	IO03NPB0V0
D9	GND	GND
D10	EMC_OEN0_N/IO03NDB0V0	EMC_OEN0_N/IO08NDB0V0
D11	EMC_AB[10]/IO09NDB0V0	EMC_AB[10]/IO11NDB0V0
D12	EMC_AB[11]/IO09PDB0V0	EMC_AB[11]/IO11PDB0V0
D13	EMC_AB[9]/IO08PDB0V0	EMC_AB[9]/IO13PDB0V0
D14	GND	GND
D15	GBC1/IO17PPB0V0	GBC1/IO22PPB0V0
D16	EMC_AB[25]/IO16PDB0V0	EMC_AB[25]/IO20PDB0V0
D17	GND	GND
D18	GBA1/IO19PPB0V0	GBA1/IO23PPB0V0
D19	NC	NC
D20	NC	NC
D21	IO21NDB1V0	IO30NDB1V0
D22	GND	GND
E1	GFC2/IO67PPB5V0	GFC2/IO84PPB5V0
E2	VCCFPGAIOB5	VCCFPGAIOB5
E3	GFA2/IO68PDB5V0	GFA2/IO85PDB5V0
E4	GND	GND

Notes:

1. Shading denotes pins that do not have completely identical functions from density to density. For example, the bank assignment can be different for an I/O, or the function might be available only on a larger density device.
2. *: Indicates that the signal assigned to the pins as a CLKBUF/CLKBUF_LVPECL/CLKBUF_LVDS goes through a glitchless mux. In order for the glitchless mux to operate correctly, the signal must be a free-running clock signal. Refer to the 'Glitchless MUX' section in the [SmartFusion Microcontroller Subsystem User's Guide](#) for more details.

Pin Number	FG484	
	A2F200 Function	A2F500 Function
L9	VCC	VCC
L10	GND	GND
L11	VCC	VCC
L12	GND	GND
L13	VCC	VCC
L14	GND	GND
L15	VCC	VCC
L16	GND	GND
L17	GNDQ	GNDQ
L18	GDA2/IO33NDB1V0	GDA2/IO42NDB1V0
L19	VCCFPGAIOB1	VCCFPGAIOB1
L20	GDB1/IO30PDB1V0	GDB1/IO39PDB1V0
L21	GDB0/IO30NDB1V0	GDB0/IO39NDB1V0
L22	GDC2/IO32PDB1V0	GDC2/IO41PDB1V0
M1	NC	IO71PDB5V0
M2	NC	IO71NDB5V0
M3	VCCFPGAIOB5	VCCFPGAIOB5
M4	NC	IO72NPB5V0
M5	GNDQ	GNDQ
M6	NC	IO68PDB5V0
M7	GND	GND
M8	VCC	VCC
M9	GND	GND
M10	VCC	VCC
M11	GND	GND
M12	VCC	VCC
M13	GND	GND
M14	VCC	VCC
M15	GND	GND
M16	VCCFPGAIOB1	VCCFPGAIOB1
M17	NC	NC
M18	GDB2/IO33PDB1V0	GDB2/IO42PDB1V0
M19	VJTAG	VJTAG
M20	GND	GND

Notes:

1. Shading denotes pins that do not have completely identical functions from density to density. For example, the bank assignment can be different for an I/O, or the function might be available only on a larger density device.
2. *: Indicates that the signal assigned to the pins as a CLKBUF/CLKBUF_LVPECL/CLKBUF_LVDS goes through a glitchless mux. In order for the glitchless mux to operate correctly, the signal must be a free-running clock signal. Refer to the 'Glitchless MUX' section in the [SmartFusion Microcontroller Subsystem User's Guide](#) for more details.

Revision	Changes	Page
Revision 10 (continued)	Corrected the Start-up time unit from "ms" to "μs" in Table 2-99 • Voltage Regulator (SAR 39395).	2-87
	Added the "References" section for "SmartFusion Development Tools" (SAR 43460).	3-1
	Updated the "References" section for Programming (SAR 43304). Added the "Application Notes on IAP Programming Technique" section (SAR 43458).	4-9
	A note was added to the "Supply Pins" table , referring to the SmartFusion cSoC Board Design Guidelines application note for details on VCCPLLx capacitor recommendations (SAR 42183).	5-1
	In the "Supply Pins" section , the VPP capacitor value section has been modified to: "For proper programming, 0.01μF, and 0.1μF to 1μF capacitors, (both rated at 16 V) are to be connected in parallel across VPP and GND, and positioned as close to the FPGA pins as possible." (SAR 43569).	5-1
	In the "User-Defined Supply Pins" section , added description 'These pins are located in Bank-2 (GPIO_16 to GPIO_31) for A2F060, A2F200, and A2F500 devices.' for GPIO_x (SAR 28595).	5-5
	Updated the MAINXIN and MAINXOUT pin descriptions in the "Special Function Pins" section to read "If an external RC network or clock input is used, the RC components are connected to the MAINXIN pin, with MAINXOUT left floating. When the main crystal oscillator is not being used, MAINXIN and MAINXOUT pins can be left floating." (SAR 42807).	5-8
	Live at Power-Up (LAPU) has been replaced with 'Instant On'.	NA
Revision 9 (September 2012)	The number of signal conditioning blocks (SCBs) for A2F500 in the "SmartFusion cSoC Family Product Table" was corrected to 4. Previously it had incorrectly been listed as 2 (SAR 39536).	II
	The "Product Ordering Codes" section was revised to clarify that only one eNVM size for each device is currently available (SAR 40333).	VI
	Information pertaining to analog I/Os was added to the "Specifying I/O States During Programming" section on page 1-3 (SAR 34836).	1-3
	The formulas in the table notes for Table 2-29 • I/O Weak Pull-Up/Pull-Down Resistances were corrected (SAR 34757).	2-27
	Maximum values for VIL and VIH were corrected in LVPECL Table 2-66 • Minimum and Maximum DC Input and Output Levels (SAR 37695).	2-43
	Minimum pulse width High and Low values were added to the tables in the "Global Tree Timing Characteristics" section . The maximum frequency for global clock parameter was removed from these tables because a frequency on the global is only an indication of what the global network can do. There are other limiters such as the SRAM, I/Os, and PLL. SmartTime software should be used to determine the design frequency (SAR 29270).	2-59
	The temperature range for accuracy in Table 2-83 • Electrical Characteristics of the RC Oscillator was changed from "0°C to 85°C" to "-40°C to 100°C" (SAR 33670). The units for jitter were changed from ps to ps RMS (SAR 34270).	2-61
	In Table 2-84 • Electrical Characteristics of the Main Crystal Oscillator , the output jitter for the 10 MHz crystal was corrected from 50 ps RMS to 1 ns RS (SAR 32939). Values for the startup time of VILXTAL were added (SAR 25248).	2-62
	In Table 2-85 • Electrical Characteristics of the Low Power Oscillator , output jitter was changed from 50 ps RMS to 30 ps RMS (SAR 32939). A value for ISTBXTAL standby current was added (SAR 25249). Startup time for a test load of 30 pF was added (SAR 27436).	2-62